

<b>Notice of References Cited</b>	Application/Control No. 09/577,209	Applicant(s)/Patent Under Reexamination VALENZUELA ET AL.	
	Examiner Ricky D. Shafer	Art Unit 2872	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Korte, "High-throughput replica optics"; Applied Optics; Vol. 27, No. 8; 15 April 1988; pp 1440-1446
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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